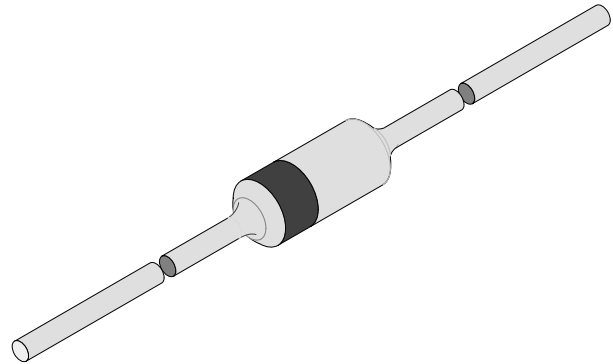


Silicon Epitaxial Planar Diode

Applications

Extreme fast switches



94 9367

Absolute Maximum Ratings

$T_j = 25^\circ\text{C}$

Parameter	Test Conditions	Type	Symbol	Value	Unit
Repetitive peak reverse voltage			V_{RRM}	75	V
Reverse voltage			V_R	50	V
Peak forward surge current	$t_p=1\mu\text{s}$		I_{FSM}	2	A
Repetitive peak forward current			I_{FRM}	500	mA
Forward current			I_F	300	mA
Average forward current	$V_R=0$		I_{FAV}	150	mA
Power dissipation	$l=4\text{mm}, T_L=45^\circ\text{C}$		P_V	440	mW
	$l=4\text{mm}, T_L \leq 25^\circ\text{C}$		P_V	500	mW
Junction temperature			T_j	175	$^\circ\text{C}$
Storage temperature range			T_{stg}	-65...+175	$^\circ\text{C}$

Maximum Thermal Resistance

$T_j = 25^\circ\text{C}$

Parameter	Test Conditions	Symbol	Value	Unit
Junction ambient	$l=4\text{mm}, T_L=\text{constant}$	R_{thJA}	350	K/W

1N4151

Characteristics

$T_j = 25^\circ\text{C}$

Parameter	Test Conditions	Type	Symbol	Min	Typ	Max	Unit
Forward voltage	$I_F=50\text{mA}$		V_F		0.88	1	V
Reverse current	$V_R=50\text{V}$		I_R		14	50	nA
	$V_R=50\text{V}, T_j=150^\circ\text{C}$		I_R			50	μA
Breakdown voltage	$I_R=5\mu\text{A}$		$V_{(BR)}$	75			V
Diode capacity	$V_R=0, f=1\text{MHz}, V_{HF}=50\text{mV}$		C_D			2	pF
Reverse recovery time	$I_F=I_R=10\text{mA}, i_R=1\text{mA}$		t_{rr}			4	ns
	$I_F=10\text{mA}, V_R=6\text{V}, i_R=0.1 \times I_R, R_L=100\Omega$		t_{rr}			2	ns

Typical Characteristics ($T_j = 25^\circ\text{C}$ unless otherwise specified)

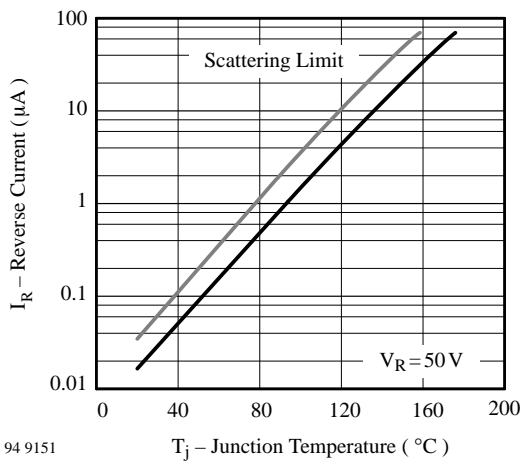


Figure 1 : Reverse Current vs. Junction Temperature

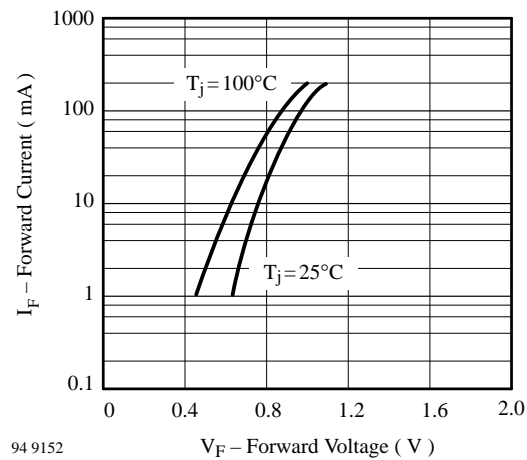


Figure 2 : Forward Current vs. Forward Voltage

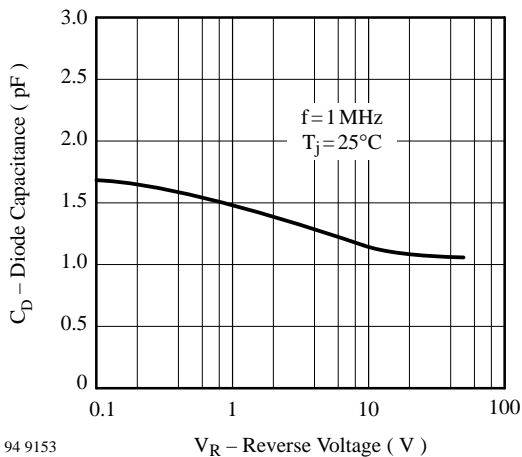


Figure 3 : Diode Capacitance vs. Reverse Voltage

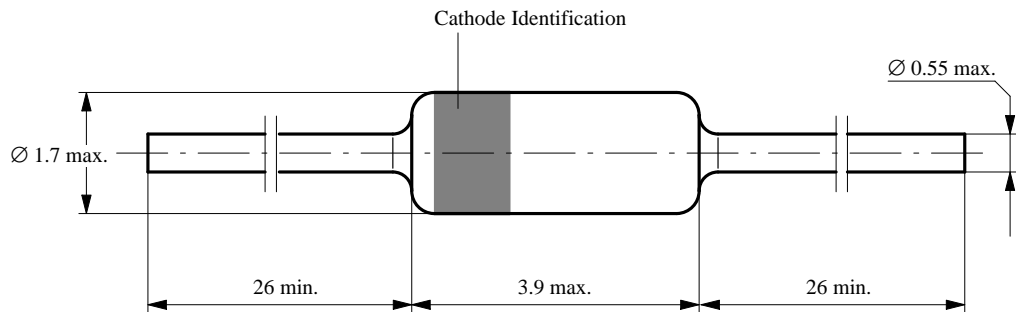
Dimensions in mm



technical drawings
according to DIN
specifications

94 9366

Standard Glass Case
54 A 2 DIN 41880
JEDEC DO 35
Weight max. 0.3 g



OZONE DEPLETING SUBSTANCES POLICY STATEMENT

It is the policy of **TEMIC TELEFUNKEN microelectronic GmbH** to

1. Meet all present and future national and international statutory requirements and
2. Regularly and continuously improve the performance of our products, processes, distribution and operating systems with respect to their impact on the health and safety of our employees and the public, as well as their impact on the environment.

Of particular concern is the control or elimination of releases into the atmosphere of those substances which are known as ozone depleting substances (ODSs).

The Montreal Protocol (1987) and its London Amendments (1990) will soon severely restrict the use of ODSs and forbid their use within the next ten years. Various national and international initiatives are pressing for an earlier ban on these substances.

TEMIC TELEFUNKEN microelectronic GmbH semiconductor division has been able to use its policy of continuous improvements to eliminate the use of any ODSs listed in the following documents.

1. Annex A, B and list of transitional substances of the Montreal Protocol and the London Amendments respectively
2. Class I and II ozone depleting substances in the Clean Air Act Amendments of 1990 by the Environmental Protection Agency (EPA) in the USA and
3. Council Decision 88/540/EEC and 91/690/EEC Annex A, B and C (transitional substances) respectively.

TEMIC can certify that our semiconductors are not manufactured with and do not contain ozone depleting substances.

We reserve the right to make changes to improve technical design without further notice.

Parameters can vary in different applications. All operating parameters must be validated for each customer application by the customer. Should the buyer use TEMIC products for any unintended or unauthorized application, the buyer shall indemnify TEMIC against all claims, costs, damages, and expenses, arising out of, directly or indirectly, any claim of personal damage, injury or death associated with such unintended or unauthorized use.

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